

Notice of References Cited

Application/Control No.

10/073,495

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

2116

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	"IEEE 100 The Authoritative Dictionary of IEEE Standards Terms", Seventh Edition, 2000.
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